

<b>Notice of References Cited</b>	Application/Control No. 10/522,572	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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*	D	US-6,538,367 B1	03-2003	Choi et al.	313/309
*	E	US-6,515,415 B1	02-2003	Han et al.	313/496
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